NX3DV3899

Dual double-pole double-throw analog switch

Rev. 3.2 — 21 June 2024 Product data sheet

1 General description

The NX3DV3899 is a dual double-pole double-throw analog data-switch suitable for use as an analog or digital multiplexer/demultiplexer. It consists of four switches, each with two independent input/outputs (nY0 and nY1) and a common input/output (nZ). The two digital inputs (1S and 2S) are used to select the switch position. Schmitt trigger action at the select input (nS) makes the circuit tolerant to slower input rise and fall times across the entire V_{CC} range from 1.4 V to 4.3 V.

A low input voltage threshold allows pin nS to be driven by lower level logic signals without a significant increase in supply current I_{CC}. This makes it possible for the NX3DV3899 to switch 4.3 V signals with a 1.8 V digital controller, eliminating the need for logic level translation. The NX3DV3899 allows signals with amplitude up to V_{CC} to be transmitted from nZ to nY0 or nY1; or from nY0 or nY1 to nZ.

2 Features and benefits

- Wide supply voltage range from 1.4 V to 4.3 V
- Very low ON resistance (peak):
  - 7.2 Ω (typical) at V_{CC} = 1.4 V
  - 5.4 Ω (typical) at V_{CC} = 1.65 V
  - 2.9 Ω (typical) at V_{CC} = 2.5 V
  - 2.4 Ω (typical) at V_{CC} = 3.0 V
  - 2.3 Ω (typical) at V_{CC} = 3.6 V
  - 2.2 Ω (typical) at V_{CC} = 4.3 V
- Break-before-make switching
- High noise immunity
- ESD protection:
  - HBM JESD22-A114F Class 2A exceeds 2000 V (all pins)
  - HBM JESD22-A114F Class 3A exceeds 5000 V (I/O pins to GND)
  - MM JESD22-A115-A exceeds 200 V
  - CDM AEC-Q100-011 revision B exceeds 1000 V
- CMOS low-power consumption
- Latch-up performance exceeds 100 mA per JESD 78B Class II Level A
- 1.8 V control logic at V_{CC} = 3.6 V
- Control input accepts voltages above supply voltage
- Very low supply current, even when input is below V_{CC}
- High current handling capability (350 mA continuous current under 3.3 V supply)
- Specified from -40 °C to +85 °C and from -40 °C to +125 °C

3 Applications

- Data switch
- Cell phone

- PDA
- Portable media player

4 Ordering information

Table 1. Ordering information

Type number	Topside marking	Package		
		Name	Description	Version
NX3DV3899HR	x99	HXQFN16(U)	plastic thermal enhanced extremely thin quad flat package; no leads; 16 terminals; body 3 mm x 3 mm x 0.5 mm	SOT1039-2
NX3DV3899GU	x9	XQFN16	plastic, extremely thin quad flat package; no leads; 16 terminals; body 1.80 x 2.60 x 0.50 mm	SOT1161-1

Table 2. Ordering options

Type number	Orderable part number	Package	Packing method	Minimum order quantity	Temperature range
NX3DV3899HR	NX3DV3899HR,115	HXQFN16(U)	REEL 7" Q1 NDP [1]	1500	-40°C to +125°C
	NX3DV3899HRZ	HXQFN16(U)	REEL 7" Q1 NDP SSB [2]	1500	-40°C to +125°C
NX3DV3899GU	NX3DV3899GU,115	XQFN16	REEL 7" Q1 NDP	4000	-40°C to +125°C

[1] Will go EOL - migrate to new leadframe NX3DV3899HRZ orderable part number.
[2] This packing method uses a Static Shielding Bag (SSB) solution. Material is to be kept in the sealed bag between uses.

5 Functional diagram

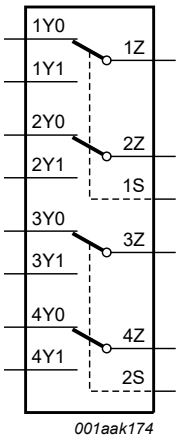


Figure 1. Logic symbol

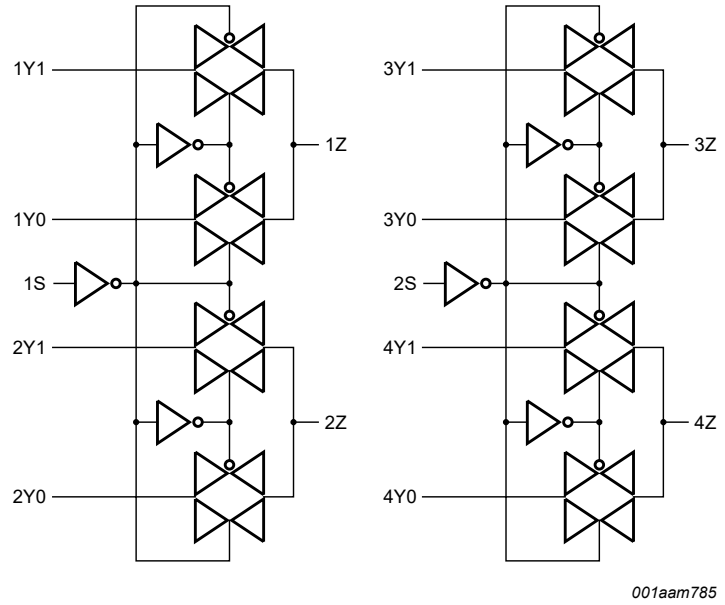
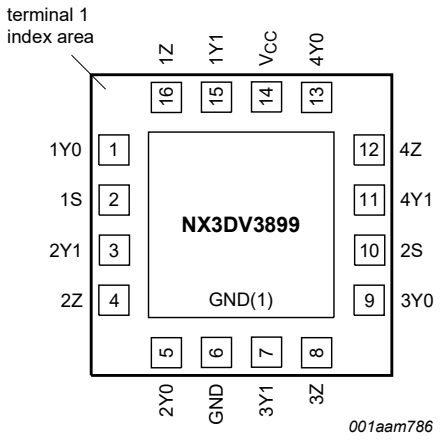


Figure 2. Logic diagram

6 Pinning information

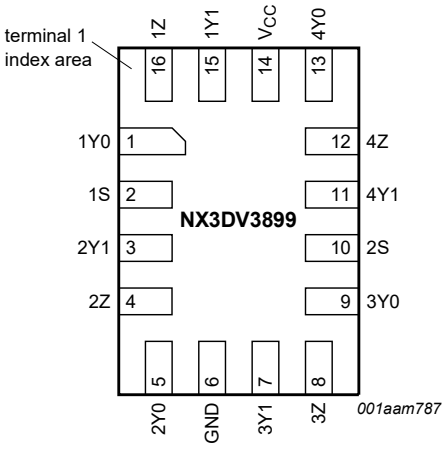
6.1 Pinning



Transparent top view

1. This is not a supply pin, the substrate is attached to this pad using conductive die attach material. There is no electrical or mechanical requirement to solder this pad however if it is soldered the solder land should remain floating or be connected to GND.

Figure 3. Pin configuration SOT1039-2 (HXQFN16(U))



Transparent top view

Figure 4. Pin configuration SOT1161-1 (XQFN16)

6.2 Pin description

Table 3. Pin description

Symbol	Pin	Description
1Y0, 2Y0, 3Y0, 4Y0	1, 5, 9, 13	independent input or output
1S, 2S	2, 10	select input
1Y1, 2Y1, 3Y1, 4Y1	15, 3, 7, 11	independent input or output
1Z, 2Z, 3Z, 4Z	16, 4, 8, 12	common output or input
GND	6	ground (0 V)
V_{CC}	14	supply voltage

7 Functional description

Table 4. Function table[1]

Input nS	Channel on
L	nY0
H	nY1

[1] H = HIGH voltage level; L = LOW voltage level.

8 Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{CC}	supply voltage			-0.5	+4.6	V
V_I	input voltage	select input nS	[1]	-0.5	+4.6	V
V_{SW}	switch voltage		[2]	-0.5	V_{CC} + 0.5	V
I_{IK}	input clamping current	V_I < -0.5 V		-50	-	mA
I_{SK}	switch clamping current	V_I < -0.5 V or V_I > V_{CC} + 0.5 V		-	±50	mA
I_{SW}	switch current	V_{SW} > -0.5 V or V_{SW} < V_{CC} + 0.5 V; source or sink current		-	±350	mA
		V_{SW} > -0.5 V or V_{SW} < V_{CC} + 0.5 V; pulsed at 1 ms duration, < 10 % duty cycle; peak current		-	±500	mA
T_{stg}	storage temperature			-65	+150	°C
P_{tot}	total power dissipation	T_{amb} = -40 °C to +125 °C				
		HXQFN16(U)	[3]	-	250	mW
		XQFN16	[4]	-	250	mW

[1] The minimum input voltage rating may be exceeded if the input current rating is observed.
[2] The minimum and maximum switch voltage ratings may be exceeded if the switch clamping current rating is observed but may not exceed 4.6 V.
[3] For HXQFN16(U) package: above 135 °C the value of P_{tot} derates linearly with 16.9 mW/K.
[4] For XQFN16 package: above 133 °C the value of P_{tot} derates linearly with 14.5 mW/K.

9 Recommended operating conditions

Table 6. Recommended operating conditions

Symbol	Parameter	Conditions		Min	Max	Unit
V_{CC}	supply voltage			1.4	4.3	V
V_I	input voltage	select input nS		0	4.3	V
V_{SW}	switch voltage		[1]	0	V_{CC}	V
T_{amb}	ambient temperature			-40	+125	°C
$\Delta t/\Delta V$	input transition rise and fall rate	V_{CC} = 1.4 V to 4.3 V	[2]	-	200	ns/V

[1] To avoid sinking GND current from terminal nZ when switch current flows in terminal nYn, the voltage drop across the bidirectional switch must not exceed 0.4 V. If the switch current flows into terminal nZ, no GND current will flow from terminal nYn. In this case, there is no limit for the voltage drop across the switch.

[2] Applies to control signal levels.

10 Static characteristics

Table 7. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground 0 V).

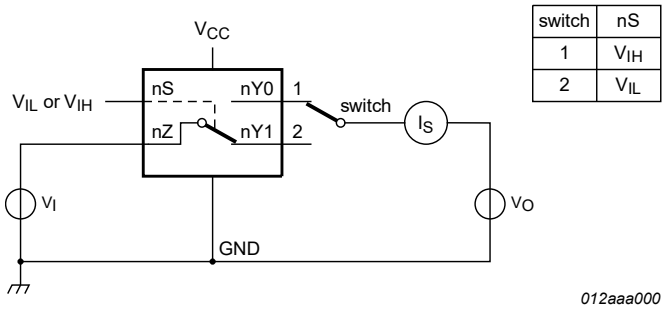
Symbol	Parameter	Conditions		T_{amb} = 25 °C			T_{amb} = -40 °C to +125 °C			Unit
				Min	Typ	Max	Min	Max (85 °C)	Max (125 °C)	
V_{IH}	HIGH-level input voltage	V_{CC} = 1.4 V to 1.6 V		0.9	-	-	0.9	-	-	V
		V_{CC} = 1.65 V to 1.95 V		0.9	-	-	0.9	-	-	V
		V_{CC} = 2.3 V to 2.7 V		1.1	-	-	1.1	-	-	V
		V_{CC} = 2.7 V to 3.6 V		1.3	-	-	1.3	-	-	V
		V_{CC} = 3.6 V to 4.3 V		1.4	-	-	1.4	-	-	V
V_{IL}	LOW-level input voltage	V_{CC} = 1.4 V to 1.6 V		-	-	0.3	-	0.3	0.3	V
		V_{CC} = 1.65 V to 1.95 V		-	-	0.4	-	0.4	0.3	V
		V_{CC} = 2.3 V to 2.7 V		-	-	0.4	-	0.4	0.4	V
		V_{CC} = 2.7 V to 3.6 V		-	-	0.5	-	0.5	0.5	V
		V_{CC} = 3.6 V to 4.3 V		-	-	0.6	-	0.6	0.6	V
I_I	input leakage current	select input nS; V_I = GND to 4.3 V; V_{CC} = 1.4 V to 4.3 V		-	-	-	-	±0.5	±1	µA
$I_{S(OFF)}$	OFF-state leakage current	nY0 and nY1 port; see Figure 5								
		V_{CC} = 1.4 V to 4.3 V		-	-	±5	-	±50	±500	nA
$I_{S(ON)}$	ON-state leakage current	nZ port; see Figure 6								
		V_{CC} = 1.4 V to 4.3 V		-	-	±5	-	±50	±500	nA
I_{CC}	supply current	V_I = V_{CC} or GND; V_{SW} = GND or V_{CC}								
		V_{CC} = 3.6 V		-	-	100	-	500	5000	nA

Table 7. Static characteristics...*continued*

At recommended operating conditions; voltages are referenced to GND (ground 0 V).

Symbol	Parameter	Conditions		T_{amb} = 25 °C			T_{amb} = -40 °C to +125 °C			Unit
				Min	Typ	Max	Min	Max (85 °C)	Max (125 °C)	
		V_{CC} = 4.3 V		-	-	150	-	800	6000	nA
ΔI_{CC}	additional supply current	V_{SW} = GND or V_{CC}								
		V_I = 2.6 V; V_{CC} = 4.3 V		-	2.0	4.0	-	7	7	µA
		V_I = 2.6 V; V_{CC} = 3.6 V		-	0.35	0.7	-	1	1	µA
		V_I = 1.8 V; V_{CC} = 4.3 V		-	7.0	10.0	-	15	15	µA
		V_I = 1.8 V; V_{CC} = 3.6 V		-	2.5	4.0	-	5	5	µA
		V_I = 1.8 V; V_{CC} = 2.5 V		-	50	200	-	300	500	nA
C_I	input capacitance			-	1.0	-	-	-	-	pF
$C_{S(OFF)}$	OFF-state capacitance			-	8	-	-	-	-	pF
$C_{S(ON)}$	ON-state capacitance			-	30	-	-	-	-	pF

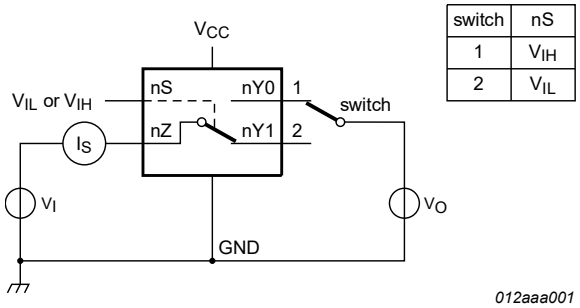
10.1 Test circuits



switch	nS
1	V_{IH}
2	V_{IL}

V_I = 0.3 V or V_{CC} - 0.3 V; V_O = V_{CC} - 0.3 V or 0.3 V.

Figure 5. Test circuit for measuring OFF-state leakage current



switch	nS
1	V_{IH}
2	V_{IL}

V_I = 0.3 V or V_{CC} - 0.3 V; V_O = V_{CC} - 0.3 V or 0.3 V.

Figure 6. Test circuit for measuring ON-state leakage current

10.2 ON resistance

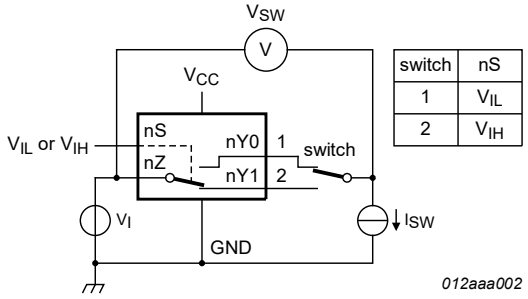
Table 8. ON resistance

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); for graphs see Figure 8 to Figure 14.

Symbol	Parameter	Conditions		T_{amb} = -40 °C to +85 °C			T_{amb} = -40 °C to +125 °C		Unit
				Min	Typ[1]	Max	Min	Max	
$R_{ON(peak)}$	ON resistance (peak)	V_I = GND to V_{CC}; I_{SW} = 100 mA; see Figure 7							
		V_{CC} = 1.4 V		-	7.2	9.3	-	10	Ω
		V_{CC} = 1.65 V		-	5.4	7.3	-	8	Ω
		V_{CC} = 2.5 V		-	2.9	3.9	-	4.5	Ω
		V_{CC} = 3.0 V		-	2.4	3.4	-	4.5	Ω
		V_{CC} = 3.6 V		-	2.3	3.3	-	4.2	Ω
		V_{CC} = 4.3 V		-	2.2	3.3	-	4.2	Ω
ΔR_{ON}	ON resistance mismatch between channels	V_I = GND to V_{CC}; I_{SW} = 100 mA	[2]						
		V_{CC} = 3.0 V		-	0.8	-	-	-	Ω
		V_{CC} = 4.3 V		-	0.7	-	-	-	Ω
$R_{ON(flat)}$	ON resistance (flatness)	V_I = GND to V_{CC}; I_{SW} = 100 mA	[3]						
		V_{CC} = 1.4 V		-	4.4	-	-	-	Ω
		V_{CC} = 1.65 V		-	2.8	-	-	-	Ω
		V_{CC} = 2.5 V		-	1.0	-	-	-	Ω
		V_{CC} = 3.0 V		-	0.8	-	-	-	Ω
		V_{CC} = 3.6 V		-	0.9	-	-	-	Ω
		V_{CC} = 4.3 V		-	1.0	-	-	-	Ω

[1] Typical values are measured at T_{amb} = 25 °C.
[2] Measured at identical V_{CC}, temperature and input voltage.
[3] Flatness is defined as the difference between the maximum and minimum value of ON resistance measured at identical V_{CC} and temperature.

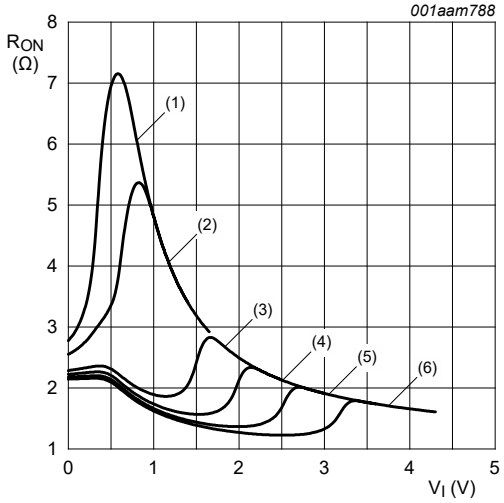
10.3 ON resistance test circuit and graphs



switch	nS
1	V_{IL}
2	V_{IH}

$R_{ON} = V_{SW} / I_{SW}$.

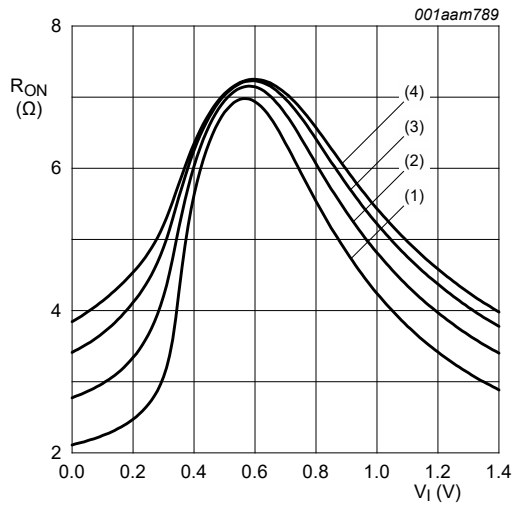
Figure 7. Test circuit for measuring ON resistance



1. V_{CC} = 1.4 V.
2. V_{CC} = 1.65 V.
3. V_{CC} = 2.5 V.
4. V_{CC} = 3.0 V.
5. V_{CC} = 3.6 V.
6. V_{CC} = 4.3 V.

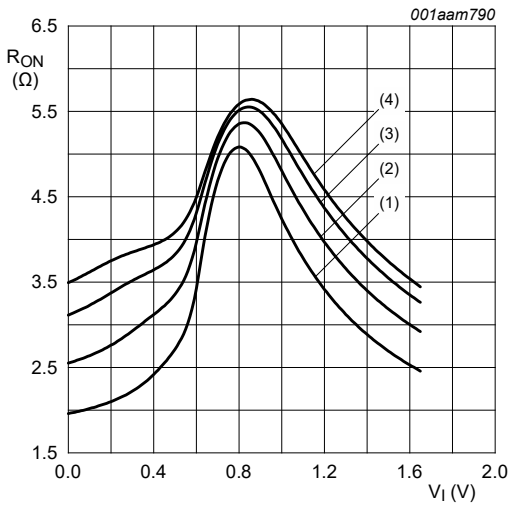
Measured at T_{amb} = 25 °C.

Figure 8. Typical ON resistance as a function of input voltage



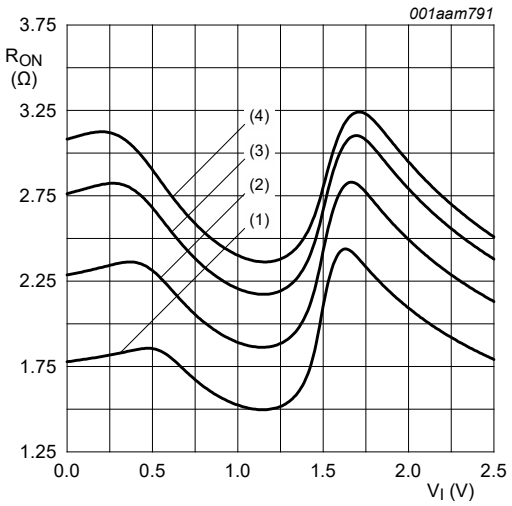
1. T_{amb} = 125 °C.
2. T_{amb} = 85 °C.
3. T_{amb} = 25 °C.
4. T_{amb} = -40 °C.

Figure 9. ON resistance as a function of input voltage; V_{CC} = 1.4 V



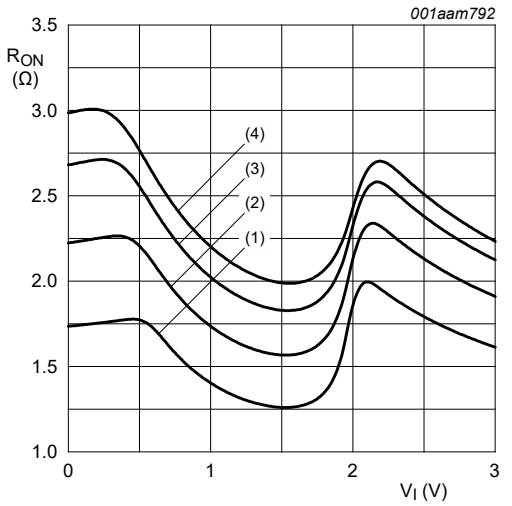
1. T_{amb} = 125 °C.
2. T_{amb} = 85 °C.
3. T_{amb} = 25 °C.
4. T_{amb} = -40 °C.

Figure 10. ON resistance as a function of input voltage; V_{CC} = 1.65 V



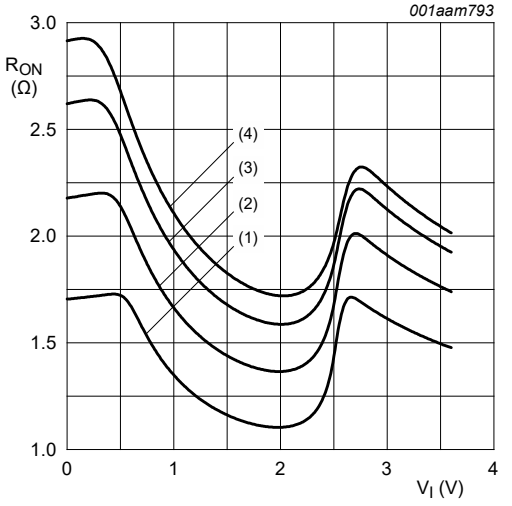
1. T_{amb} = 125 °C.
2. T_{amb} = 85 °C.
3. T_{amb} = 25 °C.
4. T_{amb} = -40 °C.

Figure 11. ON resistance as a function of input voltage; V_{CC} = 2.5 V



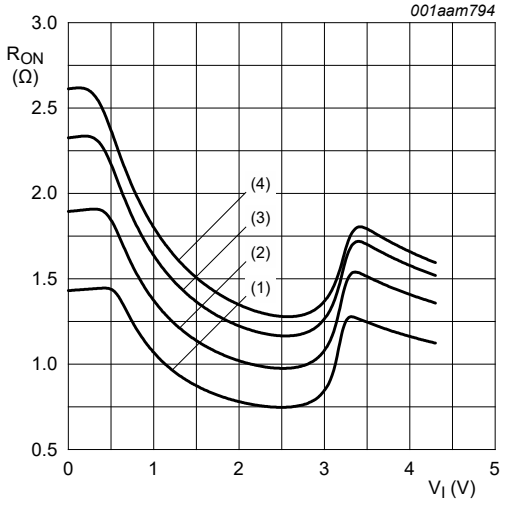
1. T_{amb} = 125 °C.
2. T_{amb} = 85 °C.
3. T_{amb} = 25 °C.
4. T_{amb} = -40 °C.

Figure 12. ON resistance as a function of input voltage; V_{CC} = 3.0 V



1. T_{amb} = 125 °C.
2. T_{amb} = 85 °C.
3. T_{amb} = 25 °C.
4. T_{amb} = -40 °C.

Figure 13. ON resistance as a function of input voltage; V_{CC} = 3.6 V



1. T_{amb} = 125 °C.
2. T_{amb} = 85 °C.
3. T_{amb} = 25 °C.
4. T_{amb} = -40 °C.

Figure 14. ON resistance as a function of input voltage; V_{CC} = 4.3 V

11 Dynamic characteristics

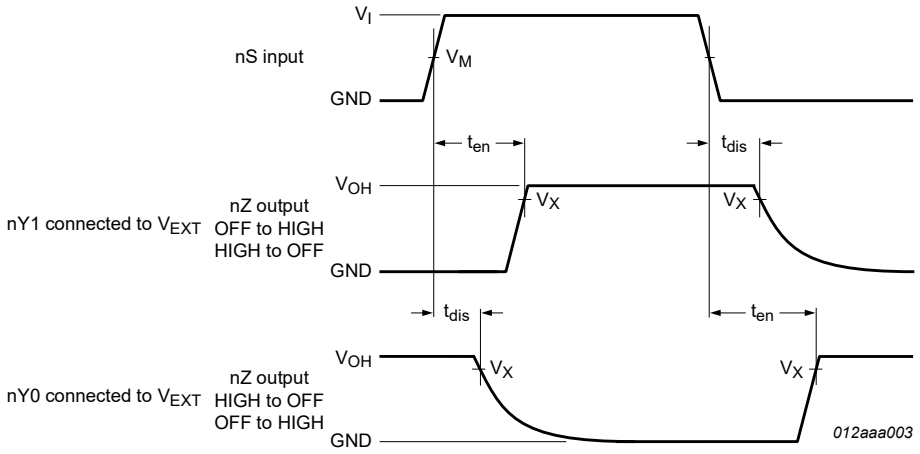
Table 9. Dynamic characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); for test circuit see Figure 17.

Symbol	Parameter	Conditions		T_{amb} = 25 °C			T_{amb} = -40 °C to +125 °C			Unit
				Min	Typ [1]	Max	Min	Max (85 °C)	Max (125 °C)	
t_{en}	enable time	nS to nZ or nYn; see Figure 15								
		V_{CC} = 1.4 V to 1.6 V		-	41	90	-	120	120	ns
		V_{CC} = 1.65 V to 1.95 V		-	30	70	-	80	90	ns
		V_{CC} = 2.3 V to 2.7 V		-	20	45	-	50	55	ns
		V_{CC} = 2.7 V to 3.6 V		-	19	40	-	45	50	ns
		V_{CC} = 3.6 V to 4.3 V		-	19	40	-	45	50	ns
t_{dis}	disable time	nS to nZ or nYn; see Figure 15								
		V_{CC} = 1.4 V to 1.6 V		-	24	70	-	80	90	ns
		V_{CC} = 1.65 V to 1.95 V		-	15	55	-	60	65	ns
		V_{CC} = 2.3 V to 2.7 V		-	9	25	-	30	35	ns
		V_{CC} = 2.7 V to 3.6 V		-	8	20	-	25	30	ns
		V_{CC} = 3.6 V to 4.3 V		-	8	20	-	25	30	ns
t_{b-m}	break-before-make time	see Figure 16	[2]							
		V_{CC} = 1.4 V to 1.6 V		-	20	-	9	-	-	ns
		V_{CC} = 1.65 V to 1.95 V		-	17	-	7	-	-	ns
		V_{CC} = 2.3 V to 2.7 V		-	13	-	4	-	-	ns
		V_{CC} = 2.7 V to 3.6 V		-	11	-	3	-	-	ns
		V_{CC} = 3.6 V to 4.3 V		-	11	-	2	-	-	ns

[1] Typical values are measured at T_{amb} = 25 °C and V_{CC} = 1.5 V, 1.8 V, 2.5 V, 3.3 V and 4.3 V respectively.
[2] Break-before-make guaranteed by design.

11.1 Waveform and test circuits



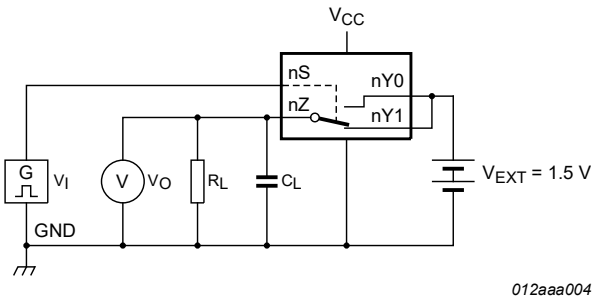
Measurement points are given in Table 10.

Logic level: V_{OH} is typical output voltage level that occurs with the output load.

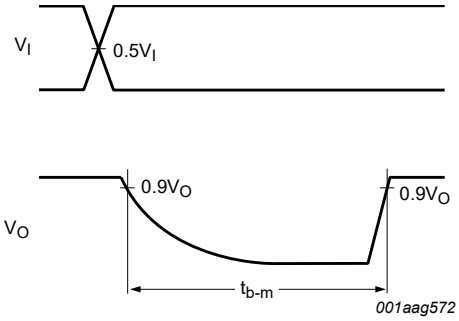
Figure 15. Enable and disable times

Table 10. Measurement points

Supply voltage	Input	Output
V_{CC}	V_M	V_X
1.4 V to 4.3 V	$0.5V_{CC}$	$0.9V_{OH}$

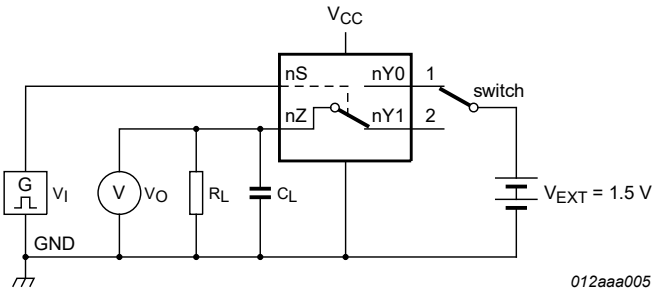


a. Test circuit



b. Input and output measurement points

Figure 16. Test circuit for measuring break-before-make timing



Test data is given in Table 11.

Definitions test circuit:

R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

V_{EXT} = External voltage for measuring switching times.

Figure 17. Test circuit for measuring switching times

Table 11. Test data

Supply voltage	Input		Load	
V_{CC}	V_I	t_r, t_f	C_L	R_L
1.4 V to 4.3 V	V_{CC}	≤ 2.5 ns	35 pF	50 Ω

11.2 Additional dynamic characteristics

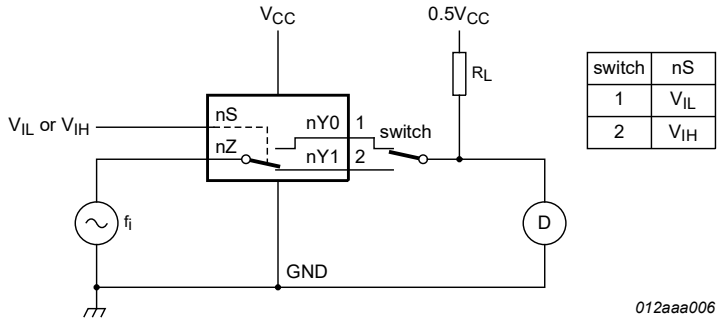
Table 12. Additional dynamic characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); V_I = GND or V_{CC} (unless otherwise specified); $t_r = t_f \leq 2.5$ ns; T_{amb} = 25 °C.

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
THD	total harmonic distortion	f_i = 20 Hz to 20 kHz; R_L = 600 Ω; see Figure 18	[1]				
		V_{CC} = 1.4 V; V_I = 1 V (p-p)		-	0.05	-	%
		V_{CC} = 1.65 V; V_I = 1.2 V (p-p)		-	0.02	-	%
		V_{CC} = 2.3 V; V_I = 1.5 V (p-p)		-	0.01	-	%
		V_{CC} = 2.7 V; V_I = 2 V (p-p)		-	0.01	-	%
		V_{CC} = 3.6 V; V_I = 2 V (p-p)		-	0.01	-	%
		V_{CC} = 4.3 V; V_I = 2 V (p-p)		-	0.01	-	%
$f_{(-3dB)}$	-3 dB frequency response	R_L = 50 Ω; see Figure 19	[1]				
		V_{CC} = 1.4 V to 4.3 V		-	200	-	MHz
α_{iso}	isolation (OFF-state)	f_i = 1 MHz; R_L = 50 Ω; see Figure 20	[1]				
		V_{CC} = 1.4 V to 4.3 V		-	-70	-	dB
V_{ct}	crosstalk voltage	between digital inputs and switch; f_i = 1 MHz; C_L = 50 pF; R_L = 50 Ω; see Figure 21					
		V_{CC} = 1.4 V to 3.6 V		-	210	-	V
		V_{CC} = 3.6 V to 4.3 V		-	300	-	V
Xtalk	crosstalk	between switches; f_i = 1 MHz; R_L = 50 Ω; see Figure 22	[1]				
		V_{CC} = 1.4 V to 4.3 V		-	-90	-	dB
Q_{inj}	charge injection	f_i = 1 MHz; C_L = 0.1 nF; R_L = 1 MΩ; V_{gen} = 0 V; R_{gen} = 0 Ω; see Figure 23					
		V_{CC} = 1.4 V		-	0.5	-	pC
		V_{CC} = 1.65 V		-	0.7	-	pC
		V_{CC} = 2.5 V		-	1.6	-	pC
		V_{CC} = 3.0 V		-	2.1	-	pC
		V_{CC} = 3.6 V		-	2.9	-	pC
		V_{CC} = 4.3 V		-	4.0	-	pC

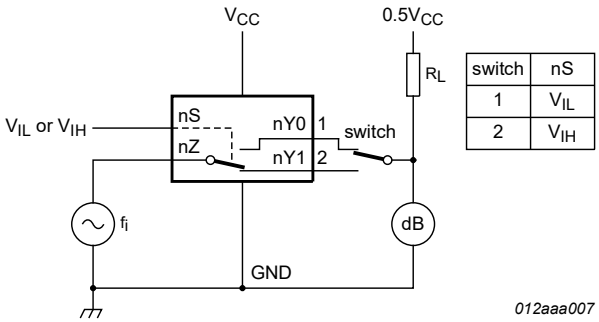
[1] f_i is biased at $0.5V_{CC}$.

11.3 Test circuits



switch	nS
1	V_{IL}
2	V_{IH}

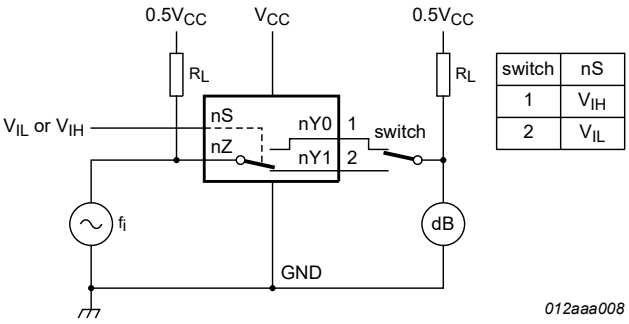
Figure 18. Test circuit for measuring total harmonic distortion



switch	nS
1	V_{IL}
2	V_{IH}

Adjust f_i voltage to obtain 0 dBm level at output. Increase f_i frequency until dB meter reads -3 dB.

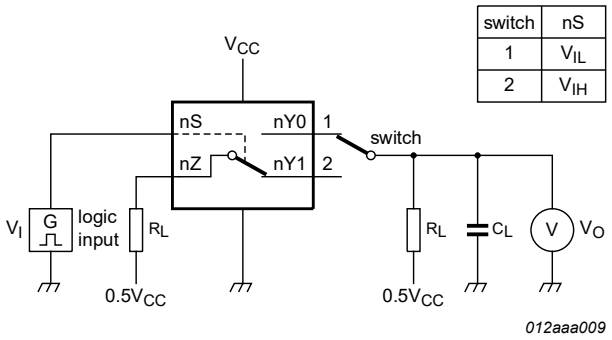
Figure 19. Test circuit for measuring the frequency response when channel is in ON-state



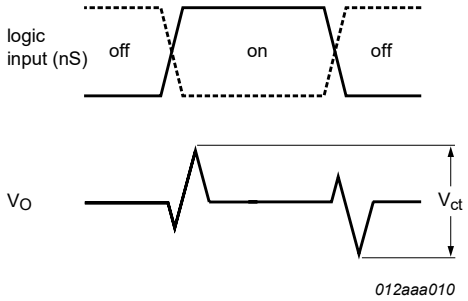
switch	nS
1	V_{IH}
2	V_{IL}

Adjust f_i voltage to obtain 0 dBm level at input.

Figure 20. Test circuit for measuring isolation (OFF-state)

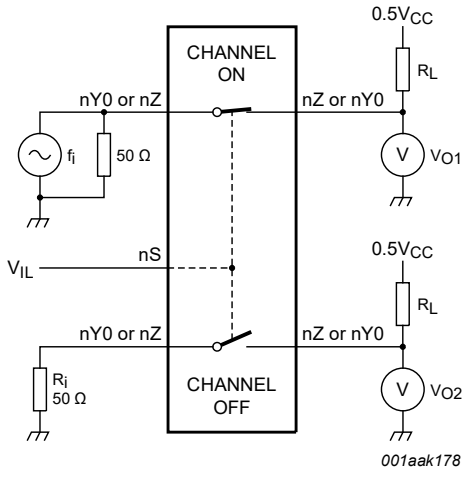


a. Test circuit



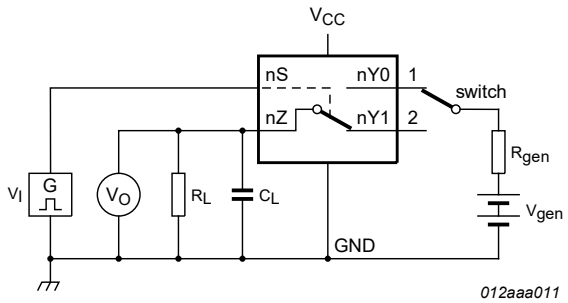
b. Input and output pulse definitions

Figure 21. Test circuit for measuring crosstalk voltage between digital inputs and switch

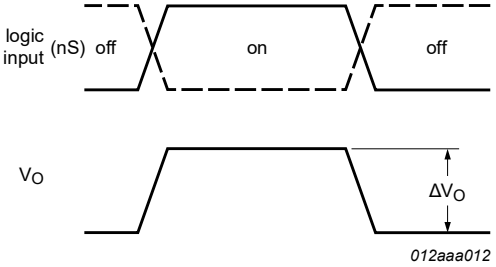


$20 \log_{10} (V_{O2} / V_{O1})$ or $20 \log_{10} (V_{O1} / V_{O2})$.

Figure 22. Test circuit for measuring crosstalk between switches



a. Test circuit



b. Input and output pulse definitions

Definition: $Q_{inj} = \Delta V_O \times C_L$.

ΔV_O = output voltage variation.

R_{gen} = generator resistance.

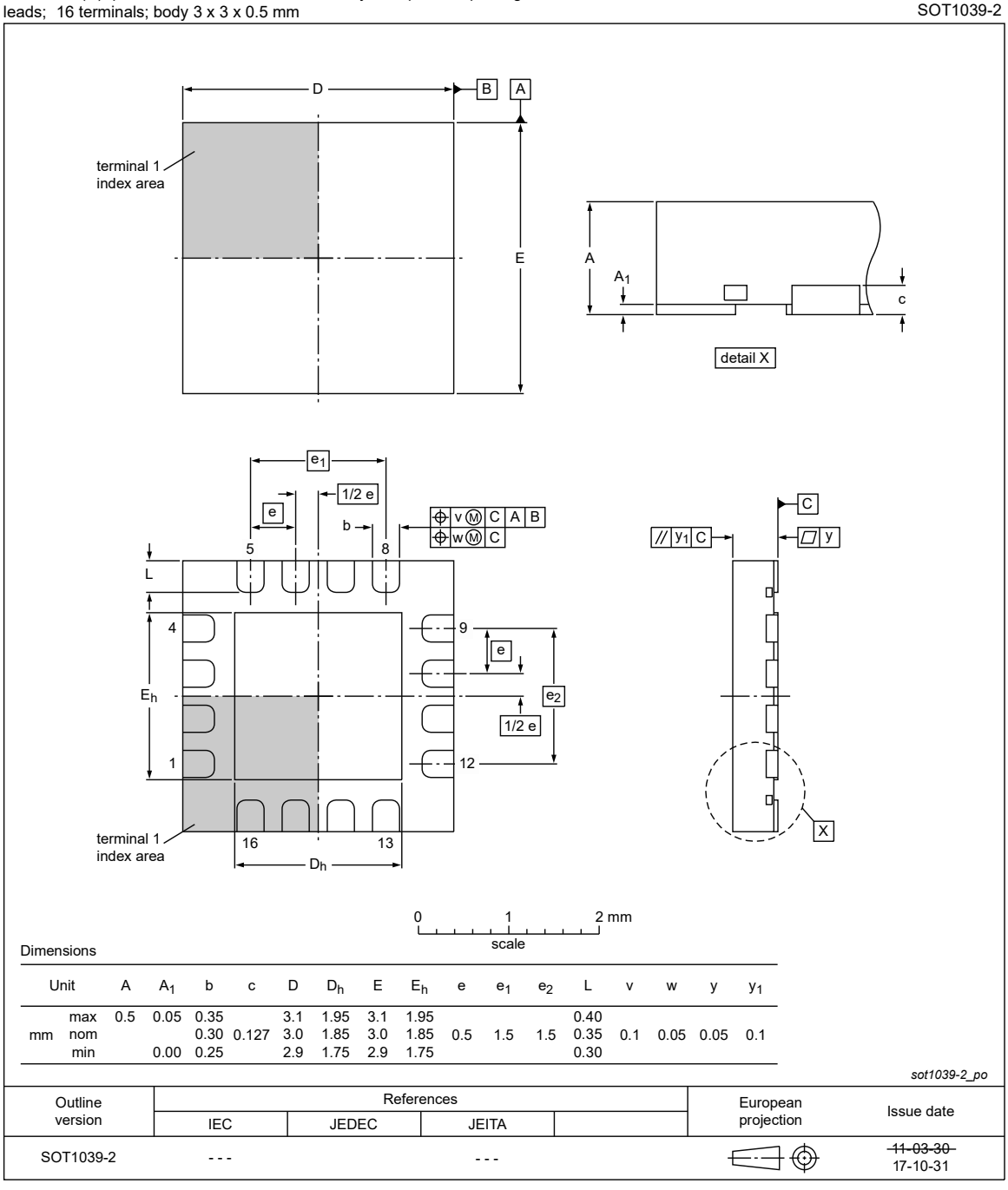
V_{gen} = generator voltage.

Figure 23. Test circuit for measuring charge injection

12 Package outline

HXQFN16(U): plastic thermal enhanced extremely thin quad flat package; no leads; 16 terminals; body 3 x 3 x 0.5 mm

SOT1039-2



Dimensions

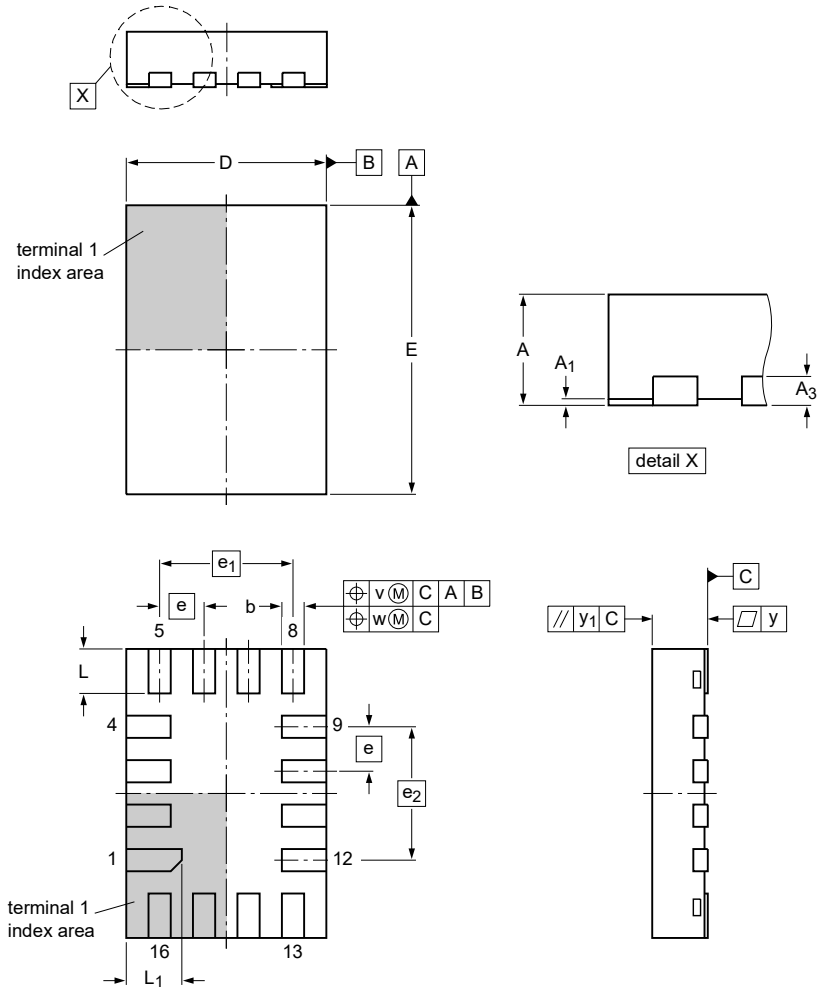
Unit		A	A_1	b	c	D	D_h	E	E_h	e	e_1	e_2	L	v	w	y	y_1
mm	max	0.5	0.05	0.35		3.1	1.95	3.1	1.95				0.40				
	nom			0.30	0.127	3.0	1.85	3.0	1.85	0.5	1.5	1.5	0.35	0.1	0.05	0.05	0.1
	min		0.00	0.25		2.9	1.75	2.9	1.75				0.30				

sot1039-2_po

Outline version	References				European projection	Issue date
	IEC	JEDEC	JEITA			
SOT1039-2	---		---			~~11-03-30~~ 17-10-31

Figure 24. Package outline SOT1039-2 (HXQFN16(U))

XQFN16: plastic, extremely thin quad flat package; no leads; 16 terminals; body 1.80 x 2.60 x 0.50 mm **SOT1161-1**



Dimensions

Unit(1)		A	A_1	A_3	b	D	E	e	e_1	e_2	L	L_1	v	w	y	y_1
mm	max	0.5	0.05		0.25	1.9	2.7				0.45	0.55				
	nom			0.127	0.20	1.8	2.6	0.4	1.2	1.2	0.40	0.50	0.1	0.05	0.05	0.05
	min		0.00		0.15	1.7	2.5				0.35	0.45				

Note
1. Plastic or metal protrusions of 0.075 mm maximum per side are not included.

sot1161-1_po

Outline version	References				European projection	Issue date
	IEC	JEDEC	JEITA			
SOT1161-1	- - -	- - -	- - -			~~09-12-28~~ 09-12-29

Figure 25. Package outline SOT1161-1 (XQFN16)

13 Abbreviations

Table 13. Abbreviations

Acronym	Description
CDM	Charged Device Model
CMOS	Complementary Metal-Oxide Semiconductor
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
PDA	Personal Digital Assistant

14 Revision history

Table 14. Revision history

Document ID	Release date	Description
NX3DV3899 v.3.2	21 June 2024	Updated per CIN 202405025I: • Corrected package outline from SOT1039-1 to SOT1039-2.
NX3DV3899 v.3.1	25 June 2021	Updated Section 4.
NX3DV3899 v.3	9 November 2011	Product data sheet; v.3
NX3DV3899 v.2	23 November 2010	Product data sheet; v.2
NX3DV3899 v.1	21 October 2010	Product data sheet; v.1

Legal information

Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.
[2] The term 'short data sheet' is explained in section "Definitions".
[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL https://www.nxp.com.

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